



# IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit [www.iecq.org](http://www.iecq.org)

## IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: **IECQ-L DEKRA 16.0002**

Issue No.: **8**

Status: **Current**

Supersedes: **IECQ-L DEKRA 16.0002 Issue 7**

Issue date: **2026-10-22** Initial: **2016-08-17**

CB Reference No.: **DEKRA-T5A-003**

Expiration: **2028-08-16**

Applicant: **Integrated Service Technology Inc.**  
No.10-1, Lixing 1st Rd., East Dist., Hsinchu City, Taiwan

The organization, facilities and procedures have been assessed by the IECQ Conformity Assessment Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of the listed standard(s) or specification(s) for the testing of component product under the IECQ:

- **ISO/IEC 17025:2017** - General requirements for the competence of testing and calibration laboratories

### Scope:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials
- See attached Schedule of Scope
- 

-- Attached schedule(s): IECQ-L DEKRA 16.0002-S\_2.pdf

Issued  
by:

**DEKRA Certification B.V.**

Meander 1051, Arnhem, Netherlands

<https://www.dekra-product-safety.com/en/about-dekra/locations/europe/netherlands/arnhem>



Authorised person: Rosa Zhou



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.  
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## Additional sites covered by this IECQ certification

IECQ Certificate No.: IECQ-L DEKRA 16.0002 Issue No.: 8

### IECQ-L DEKRA 16.0002-01

Site Added: **2016-08-17**

#### **Integrated Service Technology Inc.**

1F, No. 19/22 Pu-Ding road, Hsinchu City, 300, Taiwan, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -

### IECQ-L DEKRA 16.0002-02

Site Added: **2017-12-22**

#### **Integrated Service Technology Inc.**

No.15, Yuanqu 2nd Rd., East Dist., Hsinchu City, 30075, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -

### IECQ-L DEKRA 16.0002-03

Site Added: **2023-05-06**

#### **Integrated Service Technology Inc.**

2F.-2, No. 6, Taiyuan 1st St., Zhubei City, Hsinchu County, 302082, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -

### IECQ-L DEKRA 16.0002-04

Site Added: **2025-08-14**

#### **Integrated Service Technology Inc.**

1F., No. 38, Taiyuan St., Zhubei City, Hsinchu County, 302082, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -

### IECQ-L DEKRA 16.0002-05

Site Added: **2025-08-14**

#### **Integrated Service Technology Inc.**

4F., No. 669, Sec. 4, Zhongxing Rd., Zhudong Township, Hsinchu County, 310019, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -

### IECQ-L DEKRA 16.0002-06

Site Added: **2026-10-08**

#### **Integrated Service Technology Inc.**

6 F.-2, No. 2-1, Lixing Rd., Hsinchu Science Park, Hsinchu City 300094, Taiwan

Scope of activity at this site:

- Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials - See attached Schedule of Scope -



## Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002

CB Certificate No.: DEKRA-T5A-003

Schedule Number: IECQ-L DEKRA 16.0002-S    Rev No.: 8    Revision Date: 2026-10-22    Page 1 of 2

### Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

| Description test                                                                                                                      | Standard                                               |
|---------------------------------------------------------------------------------------------------------------------------------------|--------------------------------------------------------|
| Steady-Status Temperature and Humidity Bias Life Test (THB)                                                                           | JESD22-A101, AEC-Q100, AEC-Q101, AEC-Q200, MIL-STD-202 |
| High Humidity High Temp. Reverse Bias (H3TRB)                                                                                         | JESD22-A101, AEC-Q101                                  |
| Power and Temperature Cycling (PTC)                                                                                                   | JESD22-A105, AEC-Q100, AEC-Q101                        |
| High Temperature Operation test (HTOL)                                                                                                | JESD22-A108, AEC-Q100, AEC-Q200, MIL-STD-202           |
| Low Temperature Operation test (LTOL)                                                                                                 | JESD22-A108                                            |
| High Temperature Reverse Bias (HTRB)                                                                                                  | JESD22-A108, AEC-Q101, MIL-STD-750, MIL-STD-883        |
| High Temperature Gate Bias (HTGB)                                                                                                     | JESD22-A108, AEC-Q101                                  |
| Early Life Failure Rate (ELFR)                                                                                                        | JESD22-A108, AEC-Q100                                  |
| Highly Accelerated Stress Test (HAST)                                                                                                 | JESD22-A110, AEC-Q100, AEC-Q101                        |
| Electrically Erasable Programmable ROM (EEPROM) Program/Erase Endurance and Data Retention Stress Test (Endurance and Data Retention) | JESD22-A117, AEC-Q100,                                 |
| Power Cycling                                                                                                                         | JESD22-A122                                            |
| NVM Endurance, Data Retention, and Operation Life (EDR)                                                                               | AEC-Q100                                               |
| Electromigration (EM)                                                                                                                 | JEP001, JESD61, JESD87, AEC-Q100                       |
| Stress Migration (SM)                                                                                                                 | JEP001, JEP139, JESD87, AEC-Q100                       |
| Steady-Status operation life                                                                                                          | MIL-STD-750, MIL-STD-883                               |
| SAT                                                                                                                                   | J-STD-020                                              |
| 2D X-ray                                                                                                                              | IPC-A-610                                              |
| 3D X-ray                                                                                                                              | A00-340-30071                                          |
| 3D OM                                                                                                                                 | A00-340-30066                                          |
| Reflow test                                                                                                                           | J-STD-020                                              |
| Solderability test                                                                                                                    | J-STD-020, JESD22-B102                                 |
| Chemical Analysis                                                                                                                     | IEC62321, EN14582, IPC-TM-650                          |

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**DEKRA Certification B.V., Meander 1051, Arnhem, Netherlands**





## Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002

CB Certificate No.: DEKRA-T5A-003

Schedule Number: IECQ-L DEKRA 16.0002-S      Rev No.: 8      Revision Date: 2026-10-22      Page 2 of 2

|                                                         |                                                                                          |                                                                                                                                              |
|---------------------------------------------------------|------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------------------------------------------|
| X-section/ SEM                                          |                                                                                          | IPC-TM-650, IPC-A-610, JESD22-A121A                                                                                                          |
| OBIRCH                                                  |                                                                                          | A00-510-30003                                                                                                                                |
| InGaAs                                                  |                                                                                          | A00-510-30028                                                                                                                                |
| Thermal EMMI                                            |                                                                                          | A00-510-30038                                                                                                                                |
| Surge                                                   |                                                                                          | A00-510-30043                                                                                                                                |
| TLP                                                     |                                                                                          | A00-510-30010                                                                                                                                |
| I-V measurement                                         |                                                                                          | A00-510-30029                                                                                                                                |
| Sample Preparation (Decap)                              |                                                                                          | A00-520-30041                                                                                                                                |
|                                                         |                                                                                          |                                                                                                                                              |
| 2nd level<br>integration platform<br>service (Military) | Pre-SMT                                                                                  | J-STD-020, JESD22-A113                                                                                                                       |
|                                                         | SMT                                                                                      | IPC-7525, IPC-A-610, JESD22-A111, J-STD-002, J-STD-003, MIL-STD-202                                                                          |
|                                                         | Temperature Cycling test                                                                 | IPC-9701, JESD22-A104, JESD22-A106<br>EIAJ ED-4702, AEC-Q007, AEC-Q104<br>IEC-60068-2-14, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883 |
|                                                         | Temperature-Humidity test                                                                | JESD22-A101, MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883                                                                              |
|                                                         | Drop/Shock                                                                               | JESD22-B110, JESD22-B111, AEC-Q104<br>MIL-STD-202, MIL-STD-750, MIL-STD-810, MIL-STD-883                                                     |
|                                                         | Vibration                                                                                | JESD22-B103, AEC-Q104, MIL-STD-202<br>MIL-STD-750, MIL-STD-810, MIL-STD-883                                                                  |
|                                                         | Hermeticity                                                                              | JESD22-A109                                                                                                                                  |
|                                                         | Package Warpage Measurement of Surface-Mount Integrated Circuits at Elevated Temperature | JESD22-B108, JESD22-B112, JESD22-B110                                                                                                        |
|                                                         | Printed Wiring Board Strain Gage Test                                                    | IPC-9703                                                                                                                                     |

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